



TTTC News

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PAST TTTC EVENTS

The IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems (DDECS 2018)

25–27 April 2018

Budapest, Hungary

<https://ddecs2018.itk.ppke.hu/>

The IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems provides a forum for exchanging ideas, discussing research results, and presenting practical applications in the areas of design, test, and diagnosis of electronic circuits and systems.

Prospective authors are cordially invited to submit original papers to the symposium. Papers in English with a length of six pages maximum in the IEEE conference style are expected. Specialized student and industrial sessions, as well as embedded tutorials, will be organized at the symposium. Accepted papers will be included in the Symposium Proceedings and submitted for inclusion into the IEEE *Xplore* as well as other abstracting and indexing databases (WoS, Scopus, etc.). An extra work-in-progress session will be targeted to get early feedback on in-progress research and preliminary results (these papers will not be included in the IEEE *Xplore*).

The 23rd IEEE European Test Symposium (ETS'18)

28 May–1 June 2018

Bremen, Germany

<http://www.informatik.uni-bremen.de/ets18/>

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The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuit and system testing and reliability. In 2018, ETS will take place at Swissôtel, Bremen, Germany. It is organized by the University of Bremen, which co-sponsors the event jointly with the IEEE Council on Electronic Design Automation (CEDA). ETS traditionally enjoys a strong balance between academic and industrial participants. In addition to regular Scientific Papers, Special Sessions, Panels, and Embedded Tutorials, ETS features Vendor Sessions and Table-Top Demos as well as a special track on Emerging Test Strategies (ETS2) where new issues are presented by the industry and are discussed in an informal atmosphere. ETS is the major event of the European Test Week, which includes Test Spring School and fringe workshops.

UPCOMING TTTC EVENTS

The 24th International Symposium on On-Line Testing and Robust System Design (IOLTS'18)

2–4 July 2018

Platja d'Aro, Costa Brava, Spain

<http://tima.univ-grenoble-alpes.fr/conferences/iolts/iolts18/>

The International Symposium on On-Line Testing and Robust System Design (IOLTS) this year is held as part of the 3rd Federative Event on Design for Robustness. IOLTS explores issues related to on-line testing techniques, and more generally to design for robustness, are increasingly important in modern electronic systems. In particular, the huge complexity of electronic systems has led to growth in reliability needs in several application domains as well as pressure for low-cost products. There is a corresponding increasing demand for cost-effective design for robustness techniques. These needs have increased dramatically with the introduction of nanometer technologies, which impact adversely noise margins; process,

voltage, and temperature variations; aging and wear-out; soft error and EMI sensitivity; power density and heating; and make mandatory the use of design for robustness techniques for extending, yield, reliability, and lifetime of modern SoCs. Design for reliability also becomes mandatory for reducing power dissipation, as voltage reduction, often used to reduce power, strongly affects reliability by reducing noise margins and thus the sensitivity to soft errors and EMI, and by increasing circuit delays and thus the severity of timing faults. There is also a strong relation between Design for Reliability and Design for Security, as security attacks are often fault based.

The IOLTS is an established forum for presenting novel ideas and experimental data on these areas. The Symposium is sponsored by the IEEE CEDA and the 2018 edition is organized by the IEEE Computer Society Test Technology Technical Council, the University of Athens, and the TIMA Laboratory.

The 31st IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT'18)

8–10 October 2018

Chicago, IL, USA

<http://www.dfts.org/>

DFT is an annual symposium providing an open forum for presentations in the field of defect and fault tolerance in VLSI and nanotechnology systems inclusive of emerging technologies. One of the unique features of this symposium is to combine new

academic research with the state-of-the-art industrial data, necessary ingredients for significant advances in this field. All aspects of design, manufacturing, test, reliability, and availability which are affected by defects during manufacturing and by faults during system operation are of interest.

NEWSLETTER EDITOR'S INVITATION

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia, 1678, Cyprus; ttheocharides@ucy.ac.cy.

Theo Theocharides
Editor, TTTC Newsletter

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CONTRIBUTIONS TO THIS NEWSLETTER: Send contributions to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia 1678, Cyprus; ttheocharides@ucy.ac.cy. For more information, see the TTTC web page: <http://tab.computer.org/tttc>.